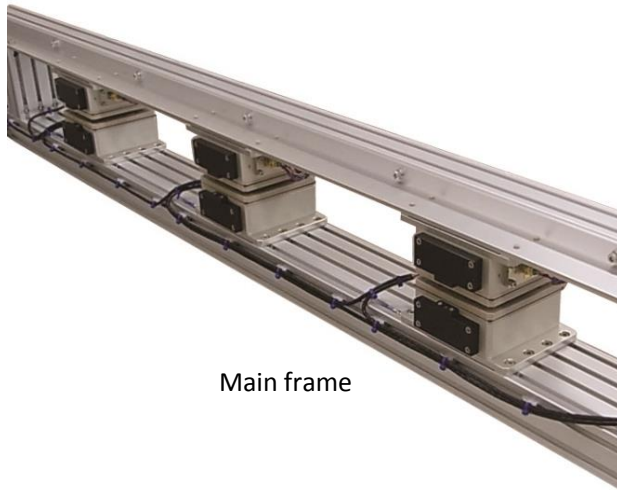
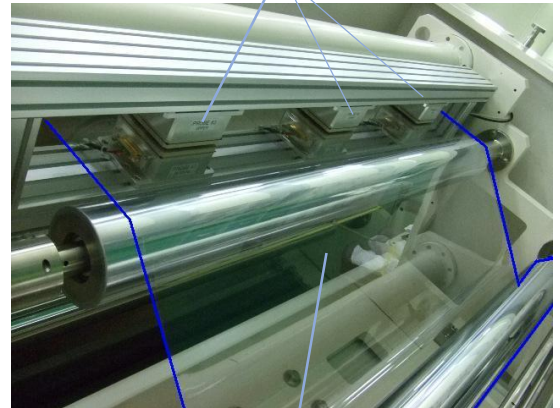


Model : NC-700

Non-contact Inline sheet resistance measurement module
for Conductive layer on substrate



Main frame



Probe head unit (Total 3 sets)

Film sample

Non-contact & Real time measurement for Roll to Roll

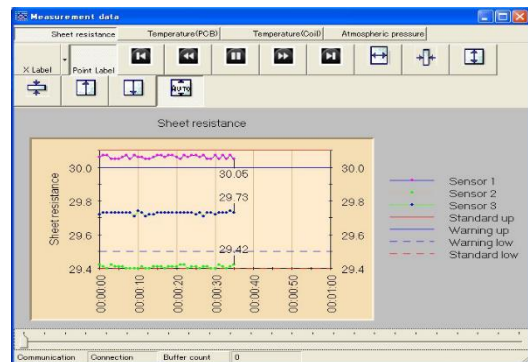
High accuracy long time measurement by "OFF-SET FREE" technology

Features

- Non-contact In-line measurement module for moving substrates such as PET film, glass or paper
- Continuous measurement(~24h) in Roll to Roll with "OFF-SET FREE" technology
[Possible to high accuracy measurement by temperature correction function]
- Various applications from the research and development to the production line
- Easy operation & monitoring by NC-700 software
- Vacuum chamber Ver.(**NC-700V**), Transmittance measurement function(**NC-700TR**) as an Option

Applications

- New materials, functional materials (Carbon nanotube, DLC, graphene, Ag nanowire etc)
- Conductive thin film (Metal, ITO etc)



Measurement Software

A global leading company for resistivity measurement system.

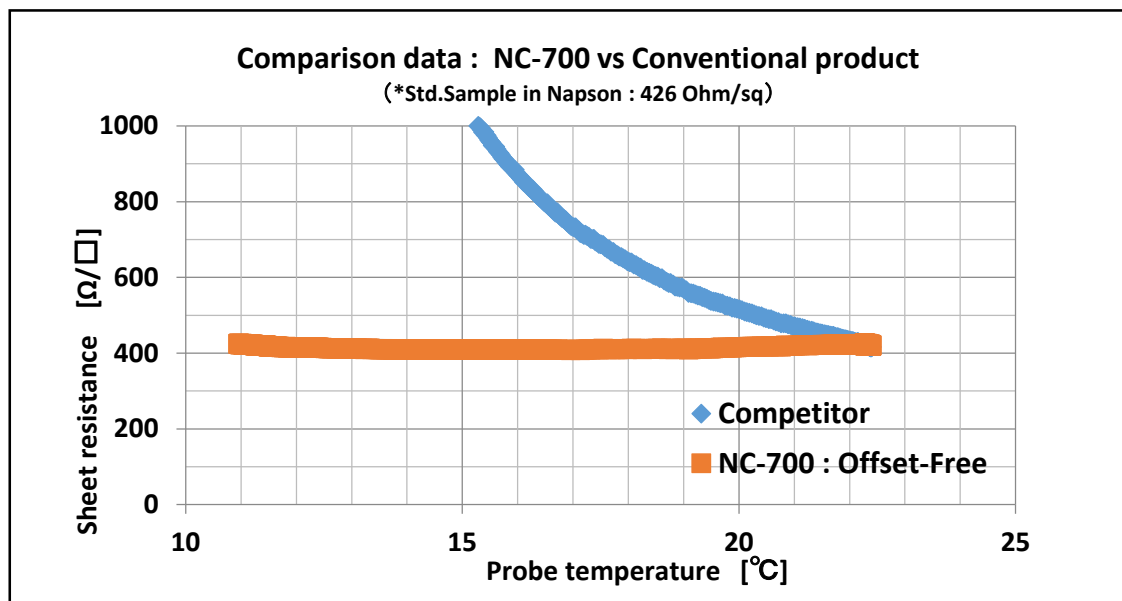


Specifications

Item	Specifications
Probe size	□60x60mm
Gap (between probes)	10mm (or Max.20mm)
Measurement Range	0.001~2000 ohm/sq (*Total range by several types of probes) *You can chose the measurement range by Min to Max;100 times or less.
Measurement repeatability	CV = 0.1 ~ 2.0% (*sample motionlessness, continuous measurement;1point/60min)
Accuracy	±1~3 % (*Correlation with 4pp system)
Continuous measurement time	Max. 24h

Napson Original : OFF-SET FREE technology

- Stable measurement data by continuous measurement. [Please refer below]
- No need to offset acquisition by operator after installation.



☆ Please visit our website for [the movie of this system](#).

*Please contact us for more details.

*The customers are always welcome to do Demo measurement.

*Specification subject to change without notice.